

Notice of References Cited

Application/Control No.

09/642,200

Applicant(s)/Patent Under
Reexamination
HAMMITT ET AL.

Examiner

Eric T. Shaffer

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,601,234	07-2003	Bowman-Amuah, Michel K.	717/108
	B	US-6,484,155	11-2002	Kiss et al.	706/46
	C	US-6,519,631	02-2003	Rosenschein et al.	709/217
	D	US-6,564,263	05-2003	Bergman et al.	709/231
	E	US-6,304,864	10-2001	Liddy et al.	706/15
	F	US-6,546,381	04-2003	Subramanian et al.	707/2
	G	US-6,505,191	01-2003	Baclawski, Kenneth P.	707/3
	H	US-5,628,011	05-1997	Ahamed et al.	707/10
	I	US-5,465,319	11-1995	Ahamed, Syed V.	706/10
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	http://www-ksl.stanford.edu/kst/what-is-an-ontology.html
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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